Atmel®

AT24CM02

I²C-Compatible (2-wire) Serial EEPROM
2-Mbit (262,144 x 8)

DATASHEET

Features

- Low Voltage and Standard Voltage Operation Available
  - 1.7V (V_{CC} = 1.7V to 5.5V)
  - 2.5V (V_{CC} = 2.5V to 5.5V)
- Internally Organized 262,144 x 8 (2-Mbit, 256-Kbyte)
- I²C-Compatible (2-wire) Serial Interface
  - 100kHz Standard Mode, 1.7V to 5.5V
  - 400kHz Fast Mode, 1.7 to 5.5V
  - 1MHz Fast Mode Plus (FM+) 2.5V to 5.5V
- Schmitt Trigger, Filtered Inputs for Noise Suppression
- Bidirectional Data Transfer Protocol
- Write Protect Pin for Full Array Hardware Data Protection
- 256-byte Page Write Mode
  - Byte Write and Partial Page Writes Allowed
- Self-timed Write Cycle
  - All Write operations complete within 10ms max
- Random and Sequential Read Modes
- Built in Error Detection and Correction
- High Reliability
  - Endurance: 1,000,000 write cycles
  - Data retention: 100 years
- Green Package Options (Lead-free/Halide-free/RoHS Compliant)
  - 8-lead JEDEC SOIC and Thin or Standard Thickness 8-ball WLCSP
- Die Sale Options: Wafer Form and Tape and Reel Available

Description

The Atmel® AT24CM02 provides 2,097,152 bits of Serial Electrically Erasable and Programmable Read-Only Memory (EEPROM) organized as 262,144 words of 8 bits each. The device's cascadable feature allows up to two devices to share a common 2-wire bus. The device is optimized for use in many industrial and commercial applications where low power and low voltage operation are essential. The device is available in space-saving 8-lead JEDEC SOIC and 8-ball WLCSP packages. In addition, the entire family is available in 1.7V (1.7V to 5.5V) and 2.5V (2.5V to 5.5V) versions.
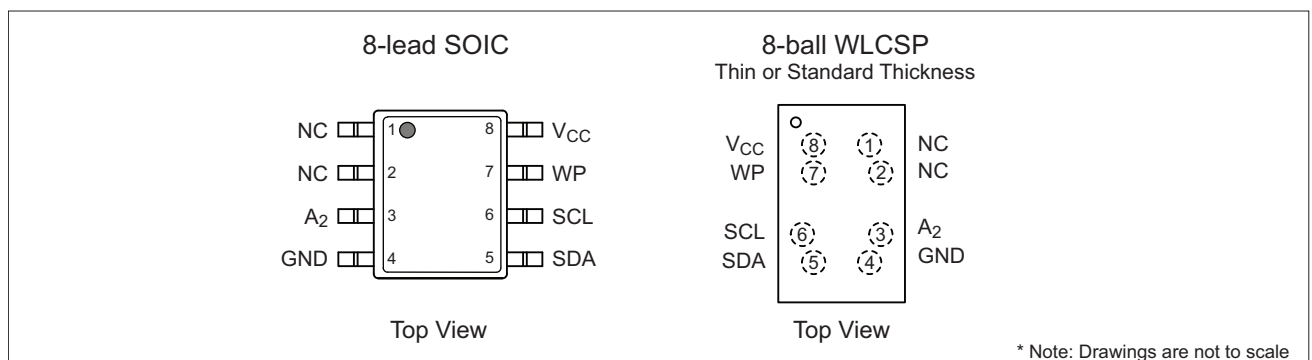
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1. Pin Descriptions and Pinouts

Table 1-1. Pin Descriptions

Pin Number	Pin Symbol	Pin Name and Functional Description	Asserted State	Pin Type
1, 2	NC	**No Connect:** The NC pin is not bonded to a die pad. This pin can be connected to GND or left floating.	—	—
3	A_2	**Device Address Inputs:** The A_2 pin is used to select the device address and corresponds to the fifth bit of the I²C seven bit slave address. This pin can be directly connected to V_{CC} or GND, allowing up to two devices on the same bus for a total of 4-Mbit of EEPROM. Refer to Note 1 for behavior of the pin when not connected.	—	Input
4	GND	**Ground:** The ground reference for the power supply. GND should be connected to the system ground.	—	Power
5	SDA	**Serial Data:** The SDA pin is an open-drain bidirectional input/output pin used to serially transfer data to and from the device. The SDA pin must be pulled-high using an external pull-up resistor (not to exceed 10KΩ in value) and may be wire-ORed with any number of other open-drain or open-collector pins from other devices on the same bus.	—	Input/ Output
6	SCL	**Serial Clock:** The SCL pin is used to provide a clock to the device and is used to control the flow of data to and from the device. Command and input data present on the SDA pin is always latched in on the rising edge of SCL, while output data on the SDA pin is always clocked out on the falling edge of SCL. The SCL pin must either be forced high when the serial bus is idle or pulled-high using an external pull-up resistor.	—	Input
7	WP	**Write Protect:** Connecting the WP pin to GND will ensure normal write operations. When WP is connected to V_{CC} all write operations to the memory are inhibited. Refer to Note 1 for behavior of the pin when not connected.	High	Input
8	V_{CC}	**Device Power Supply:** The V_{CC} pin is used to supply the source voltage to the device. Operations at invalid V_{CC} voltages may produce spurious results and should not be attempted.	—	Power

Note: 1. If either the A_2 pin or the WP pin are not driven, they are internally pulled down to GND. In order to operate in a wide variety of application environments, the pull-down mechanism is intentionally designed to be somewhat strong. Once these pins are biased above the CMOS input buffer's trip point (~0.5 x V_{CC}), the pull-down mechanism disengages. In any case, Atmel recommends connecting these pins to a known state whenever possible.

8-lead SOIC

NC — 1 ● / 8 — V_{CC}
NC — 2 / 7 — WP
A_2 — 3 / 6 — SCL
GND — 4 / 5 — SDA

Top View

8-ball WLCSP
Thin or Standard Thickness

V_{CC} WP — 8 7 / 1 2 — NC NC
SCL SDA — 6 5 / 3 4 — A_2 GND

Top View

* Note: Drawings are not to scale

2.   Device Block Diagram and System Configuration

Figure 2-1.   Block Diagram
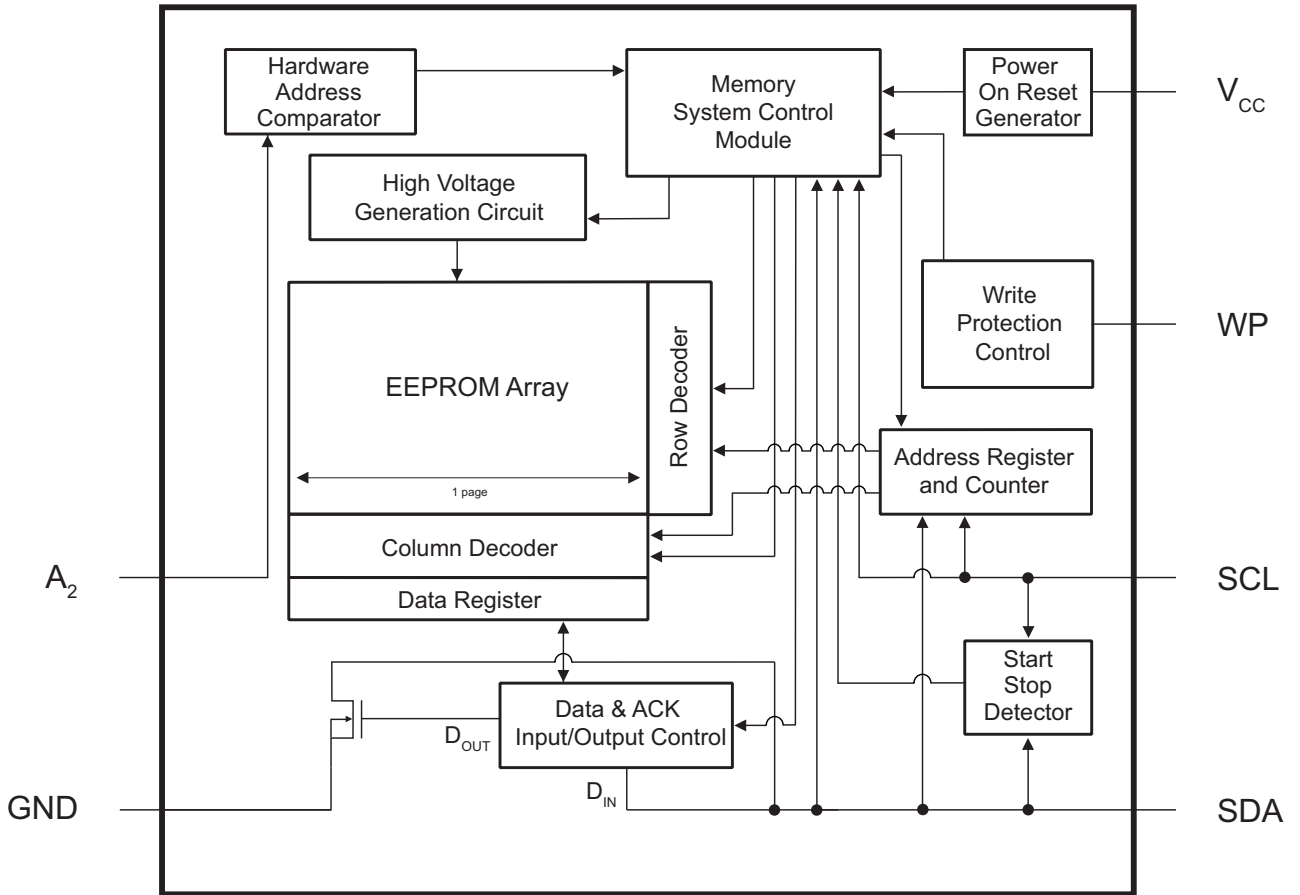
Figure 2-2.   System Configuration Using 2-Wire Serial EEPROMs

$$R_{PUP(max)} = \frac{t_{R(max)}}{0.8473 \times C_L}$$

$$R_{PUP(min)} = \frac{V_{CC} - V_{OL(max)}}{I_{OL}}$$
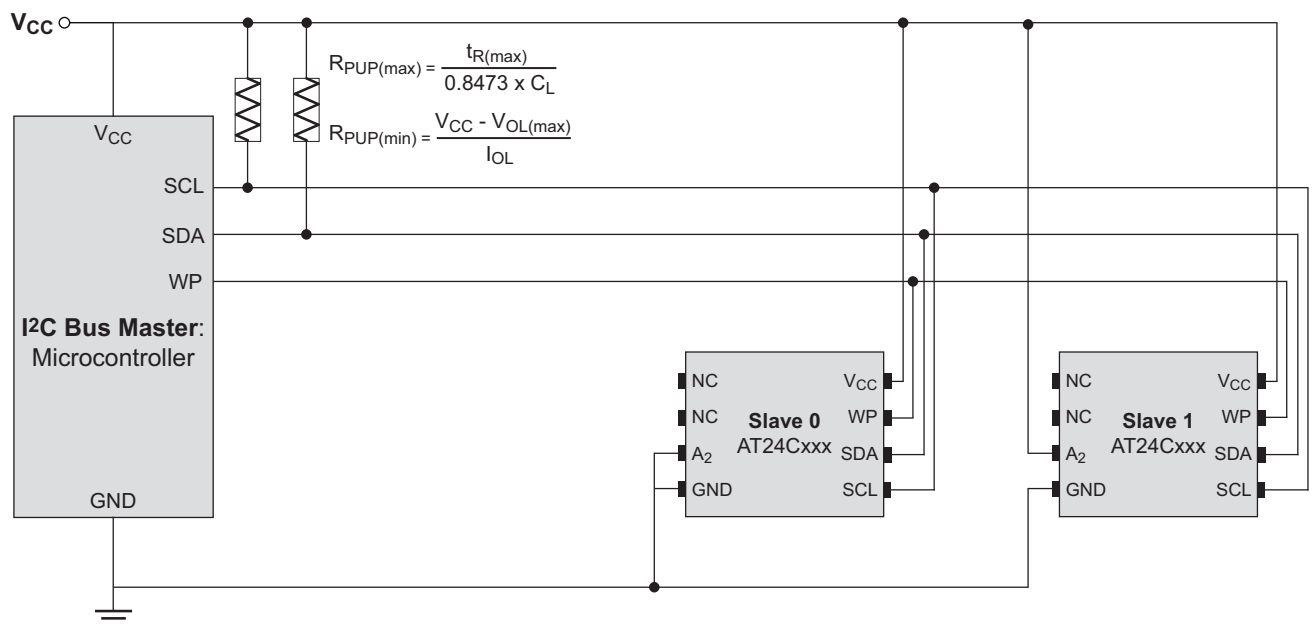
3. Device Operation and Communication

The AT24CM02 operates as a slave device and utilizes a simple I^{2}C-compatible 2-wire digital serial interface to communicate with a host controller, commonly referred to as the bus Master. The Master initiates and controls all Read and Write operations to the slave devices on the serial bus, and both the Master and the slave devices can transmit and receive data on the bus.

The serial interface is comprised of just two signal lines: Serial Clock (SCL) and Serial Data (SDA). The SCL pin is used to receive the clock signal from the Master, while the bidirectional SDA pin is used to receive command and data information from the Master as well as to send data back to the Master. Data is always latched into the AT24CM02 on the rising edge of SCL and always output from the device on the falling edge of SCL. Both the SCL and SDA pin incorporate integrated spike suppression filters and Schmitt Triggers to minimize the effects of input spikes and bus noise.

All command and data information is transferred with the Most-Significant Bit (MSB) first. During bus communication, one data bit is transmitted every clock cycle, and after eight bits (one byte) of data have been transferred, the receiving device must respond with either an acknowledge (ACK) or a no-acknowledge (NACK) response bit during a ninth clock cycle (ACK/NACK clock cycle) generated by the Master. Therefore, nine clock cycles are required for every one byte of data transferred. There are no unused clock cycles during any Read or Write operation, so there must not be any interruptions or breaks in the data stream during each data byte transfer and ACK or NACK clock cycle.

During data transfers, data on the SDA pin must only change while SCL is low, and the data must remain stable while SCL is high. If data on the SDA pin changes while SCL is high, then either a Start or a Stop condition will occur. Start and Stop conditions are used to initiate and end all serial bus communication between the Master and the slave devices. The number of data bytes transferred between a Start and a Stop condition is not limited and is determined by the Master. In order for the serial bus to be idle, both the SCL and SDA pins must be in the logic high state at the same time.

3.1 Clock and Data Transition Requirements

The SDA pin is an open drain terminal and therefore must be pulled high with an external pull-up resistor. Data on the SDA pin may change only during SCL low time periods. The SCL pin must be forced high when the serial bus is idle, therefore an external pull-up resistor is recommended. Data changes during SCL high periods will indicate a Start or Stop condition as defined below.

3.2 Start and Stop Conditions

3.2.1 Start Condition

A Start condition occurs when there is a high-to-low transition on the SDA pin while the SCL pin is stable in the Logic 1 state. The Master uses a Start condition to initiate any data transfer sequence, therefore the Start condition must precede any command. The AT24CM02 will continuously monitor the SDA and SCL pins for a Start condition but the device will not respond unless one is given. Please refer to Figure 3-1 for more details.

3.2.2 Stop Condition

A Stop condition occurs when there is a low-to-high transition on the SDA pin while the SCL pin is stable in the Logic 1 state. The Master uses the Stop condition to end a data transfer sequence to the AT24CM02 which will subsequently return to the idle state. The Master can also utilize a repeated Start condition instead of a Stop condition to end the current data transfer if the Master will perform another operation. Please refer to Figure 3-1 for more details.

3.3 Acknowledge and No-Acknowledge

After every byte of data is received, the receiving device must confirm to the Master that it has successfully received the data byte by responding with what is known as an acknowledge (ACK). An ACK is accomplished by the transmitting device first releasing the SDA line at the falling edge of the eighth clock cycle followed by the receiving device responding with a Logic 0 during the entire high period of ninth clock cycle.

When the AT24CM02 is transmitting data to the Master, the Master can indicate that it is done receiving data and wants to end the operation by sending a Logic 1 response to the AT24CM02 instead of an ACK response during the ninth clock cycle. This is known as a no-acknowledge (NACK) and when the Master sends this Logic 1 during the ninth clock cycle, the AT24CM02 will release the SDA line so that the Master can then generate a Stop or Start condition.

The transmitting device, which can be the bus Master or the Serial EEPROM, must release the SDA line at the falling edge of the eighth clock cycle to allow the receiving device to pull the SDA line low to ACK the previous 8-bit word. The receiving device must release the SDA line at the end of the ninth clock cycle to allow the transmitter to continue sending new data. A timing diagram has been provided in Figure 3-1 to better illustrate these requirements.

Figure 3-1.   Start Condition, Data Transitions, Stop Condition and Acknowledge
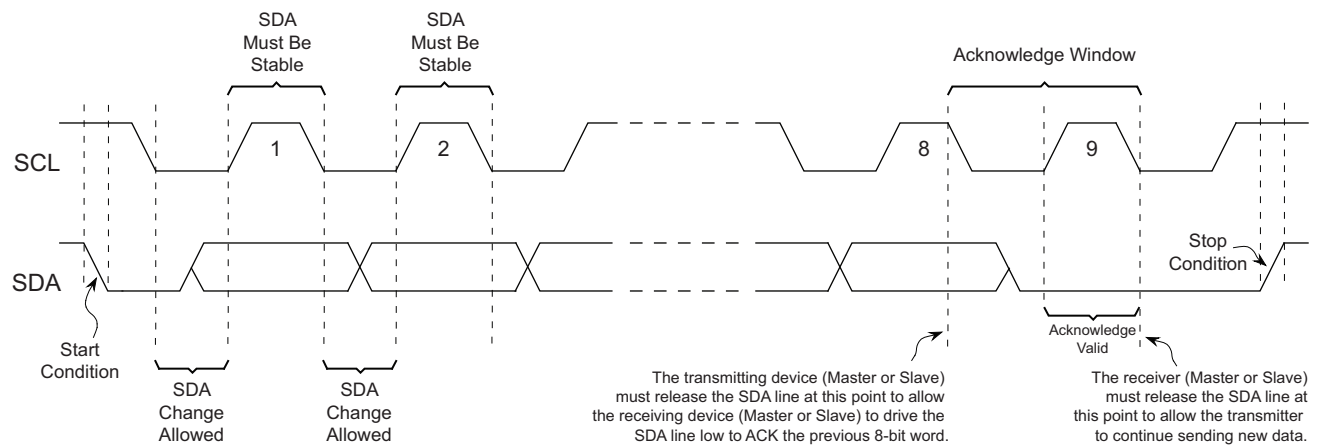
The relationship of the AC timing parameters with respect to SCL and SDA for the AT24CM02 are show in Figure 8-1 timing waveform on page 15. The AC timing characteristics and specifications are outlined in Section 8.4 "AC Characteristics" on page 15.

3.4 Standby Mode

The AT24CM02 features a low power standby mode which is enabled when:

- A valid power-up sequence is performed (see Section 8.5).
- A Stop condition received by the device unless it initiates an internal write cycle (see Section 5.).
- At the completion of an internal write cycle (see Section 5.).
- An unsuccessful match of the device type identifier or hardware address in the Device Address byte (see Section 4.1).
- The bus Master does not ACK the receipt of data read out from the device; instead it sends a NACK response (see Section 6.).

3.5   Software Reset

After an interruption in protocol, power loss, or system reset, any 2-wire part can be protocol reset by following these steps:

1.   Create a Start condition (if possible).
2.   Clock nine cycles.
3.   Create another Start condition followed by a Stop condition as seen in Figure 3-2.

The device should be ready for the next communication after above steps have been completed. In the event that the device is still non-responsive or remains active on the SDA bus, a power cycle must be used to reset the device (see Section 8.5.1 "Device Reset").

Figure 3-2.   Software Reset
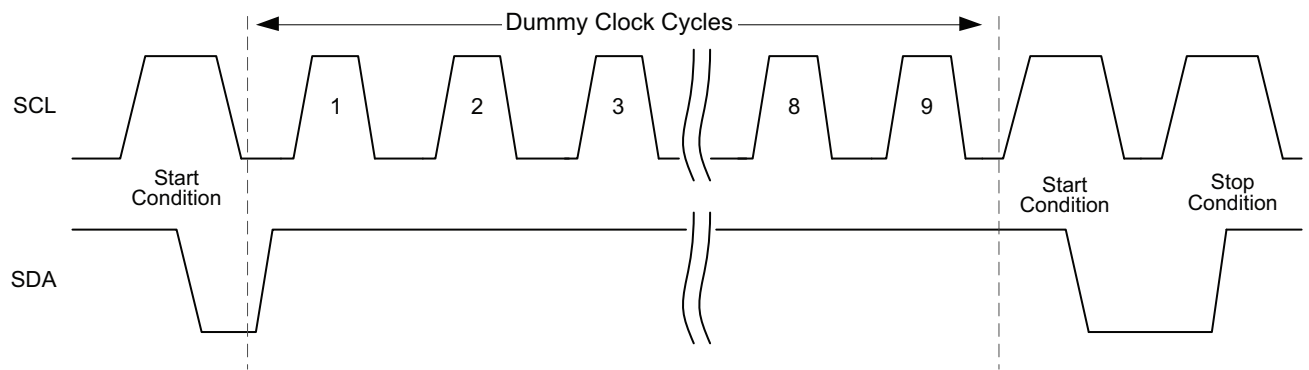
4. Memory Organization

The AT24CM02 is internally organized as 1,024 pages of 256 bytes each.

4.1 Device Addressing

The most significant 4 bits of the device address word is referred to as the device type identifier. The AT24CM02 will respond to the device type identifier `1010b` (Ah) in bit seven through bit four positions of the device address byte (see Table 4-1).

Following the 4-bit device type identifier (bit 3) is the hardware address bit, A_2. This bit can be used to expand the contiguous address space to a total of 4-Mbit by allowing up to two AT24CM02 devices on the same bus. The A_2 value must correlate with the voltage level on the corresponding hardwired input pin, A_2.

The A_2 pin uses an internal proprietary circuit that automatically biases it to a Logic 0 state if any of the pins are allowed to float. In order to operate in a wide variety of application environments, the pull-down mechanism is intentionally designed to be somewhat strong. Once the pin is biased above the CMOS input buffer's trip point (~0.5 x V_{CC}), the pull-down mechanism disengages. Atmel recommends connecting the A_2 pin to a known state whenever possible.

The next bits in the device address byte are A17 (bit 2) and A16 (bit 1) which are the most significant bits of the data Word Address that follows in the subsequent two bytes.

The eighth bit of the device address (bit 0) is the read/write operation select bit. A read operation is initiated if this bit is a Logic 1 and a write operation is initiated if this bit is Logic 0.

Upon a successful comparison of the device address, the EEPROM will return an ACK. If a valid comparison is not made, the device will NACK and return to a standby state.

Table 4-1. Device Address Byte

Package Type	Device Type Identifier				Hardware Address Bit	MSB Address Bits		Read/Write
	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
SOIC, WLCSP	1	0	1	0	A_2	A17	A16	R/$\overline{W}$

For all operations except the Current Address Read, a two-byte Word Address must be transmitted to the device immediately following the Device Address byte. The Word Address bytes contain the lower sixteen significant memory array address bits, and is used to specify which location in the EEPROM to start reading or writing. Please refer to Table 4-2 and Table 4-3 to review these bit positions.

Table 4-2. First Word Address Byte

Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
A15	A14	A13	A12	A11	A10	A9	A8

Table 4-3. Second Word Address Byte

| Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
A7	A6	A5	A4	A3	A2	A1	A0

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5.   Write Operations

All write operation sequences for the AT24CM02 begin with Master sending a Start condition, followed by a device address byte with the R/W bit set to Logic 0, and then by the first and second Word Address bytes. The data value(s) to be written to the device immediately follow the Word Address bytes.

5.1   Byte Write

The AT24CM02 supports writing of single 8-bit bytes. Selecting a data word in the 2-Mbit memory requires an 18-bit word address. This 18-bit word address field consists of the A17 and A16 bits in the Device Address byte followed by the first and second Word Address bytes in the next two bytes.

Upon receipt of the proper Device Address and Word Address bytes, the EEPROM will send an Acknowledge. The device will then be ready to receive the first 8-bit data word. Following receipt of the 8-bit data word, the EEPROM will respond with an Acknowledge. The addressing device, such as a bus Master, must then terminate the write sequence with a Stop condition. At that time the EEPROM will enter an internally self-timed write cycle, which will complete within a time of tWR, while the data word is being programmed into the nonvolatile EEPROM. All inputs are disabled during this write cycle and the EEPROM will not respond until the write is complete.

Figure 5-1.   Byte Write
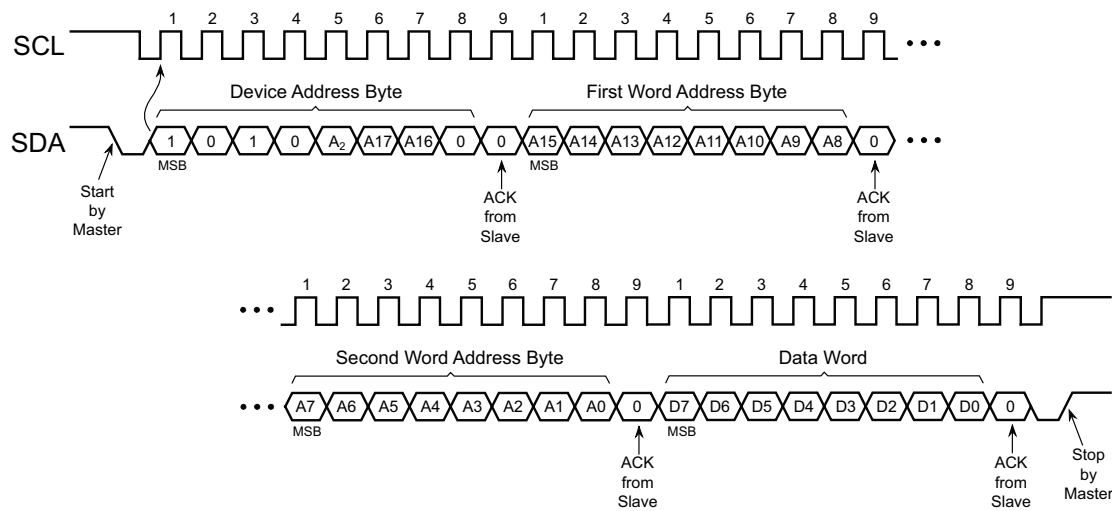
5.2   Page Write

A Page Write operation allows up to 256 bytes to be written in the same write cycle, provided that all bytes are in the same row of the memory array (where address bits A17 through A8 are the same). Partial Page Writes of less than 256 bytes are allowed.

A Page Write is initiated the same way as a Byte Write, but the bus Master does not send a Stop condition after the first data word is clocked in. Instead, after the EEPROM acknowledges receipt of the first data word, the bus Master can transmit up to 255 additional data words. The EEPROM will respond with an ACK after each data word is received. The bus Master must terminate the Page Write operation with a Stop condition (see Figure 5-2) at which time the internally self-timed write cycle will begin.

The lower eight bits of the word address are internally incremented following the receipt of each data word. The higher order address bits are not incremented, and retain the memory page row location. Page Write operations are limited to writing bytes within a single physical page, regardless of the number of bytes actually being written. When the incremented word address reaches the page boundary, the address counter will "roll over" to the beginning of the same page. Nevertheless, creating a roll over event should be avoided as previously loaded data in the page could become unintentionally altered during the write cycle.

Figure 5-2.   Page Write
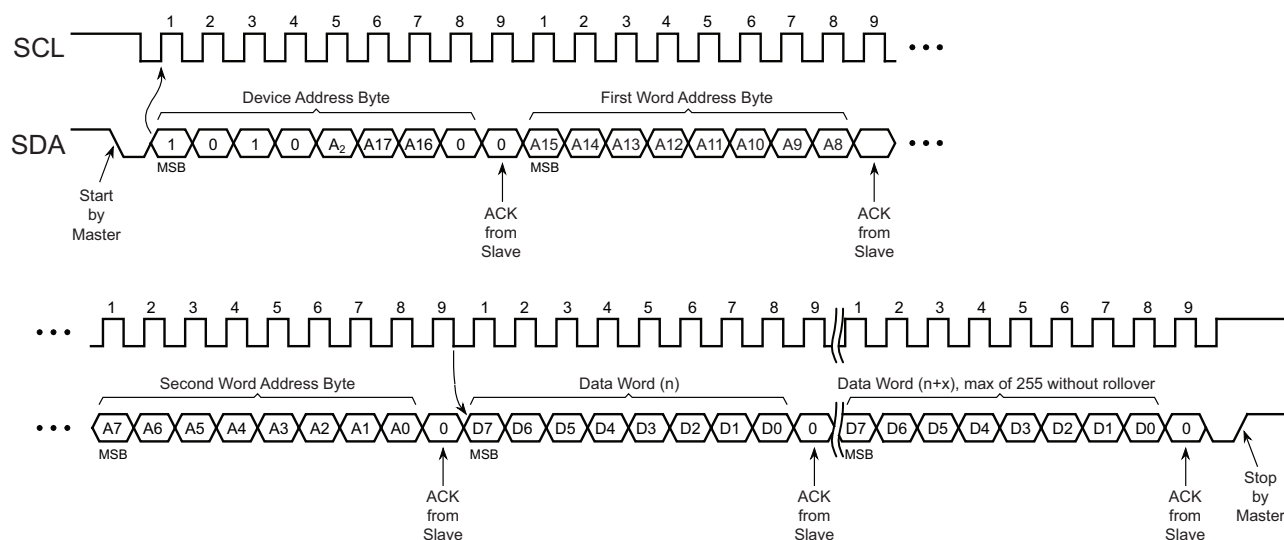
5.3   Internal Writing Methodology

The AT24CM02 incorporates a built in error detection and correction (EDC) logic scheme. The EEPROM array is internally organized as a group of four connected 8-bit bytes plus an additional six ECC (Error Correction Code) bits of EEPROM. These 38 bits are referred to as the internal physical data word. During a read sequence, the EDC logic compares each 4-byte physical data word with its corresponding six ECC bits. If a single bit out of the 4-byte region reads incorrectly, the EDC logic will detect the bad bit and replace it with the correct value before the data is serially clocked out. This architecture significantly improves the reliability of the AT24CM02 compared to an implementation that does not utilize EDC.

It is important to note that data is always physically written to the part at the internal physical data word level, regardless of the number of bytes written. Writing single bytes is still possible with the Byte Write operation, but internally, the other three bytes within that 4-byte location where the single byte was written, along with the six ECC bits will be updated. Due to this architecture, the AT24CM02 EEPROM write endurance is rated at the internal physical data word level (4-byte word). The system designer needs to optimize the application writing algorithms to observe these internal word boundaries in order to reach the 1,000,000 cycle endurance rating.

5.4   Acknowledge Polling

An Acknowledge Polling routine can be implemented to optimize time sensitive applications that would prefer to not wait the fixed maximum write cycle time (t_{WR}). This method allows the application to know immediately when the Serial EEPROM write cycle has completed, so a subsequent operation can begin.

Once the internally self-timed write cycle has started, an Acknowledge Polling routine can be initiated. This involves repeatedly sending a Start condition followed by a valid device address byte. The device will not respond with an ACK while the write cycle is ongoing. Once the internal write cycle has completed, the EEPROM will respond with an ACK, allowing a new read or write sequence to be initiated.

Figure 5-3.   Acknowledge Polling Flow Chart

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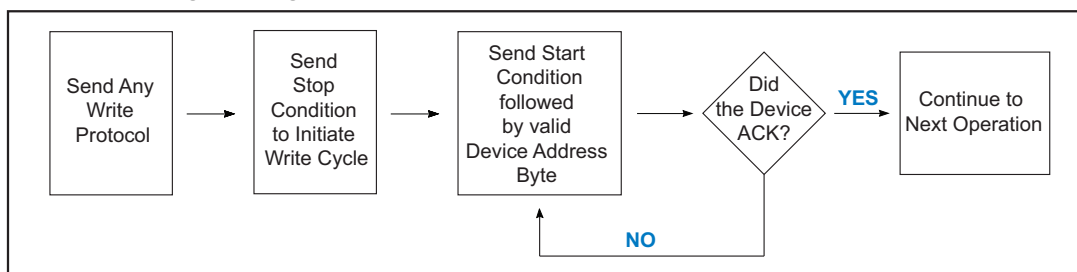
5.5 Write Cycle Timing

The length of the self-timed write cycle, or t_{WR}, is defined as the amount of time from the valid Stop condition that begins the internal write operation, to the Start condition of the first device address byte sent to the AT24CM02 that it subsequently responds to with an ACK. The figure below has been included to show this measurement.

Figure 5-4.   Write Cycle Timing

First Acknowledge from the device to a valid device address sequence after write cycle is initiated. The minumum t_{WR} can only be determined through the use of an ACK Polling routine.
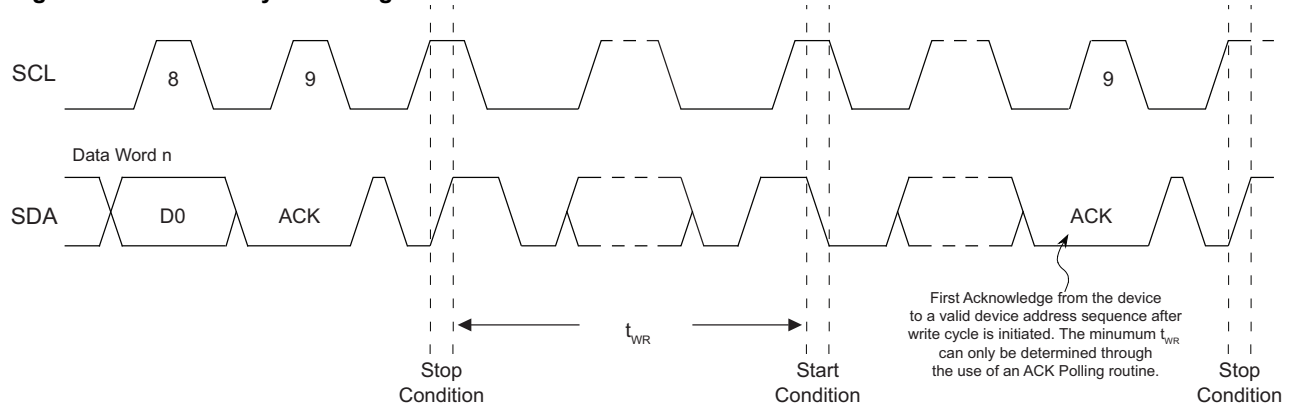
5.6 Write Protection

The AT24CM02 utilizes a hardware data protection scheme that allows the user to write protect the entire memory contents when the WP pin is at V_{CC}. No write protection exists if the WP pin is at GND or left floating.

Table 5-1.   AT24CM02 Write Protect Behavior

WP Pin Voltage	Part of the Array Protected
V_{CC}	Full Array
GND	None — Write Protection Not Enabled

The status of the WP pin is sampled at the Stop condition for every Byte Write or Page Write command prior to the start of an internally self-timed Write operation. Changing the WP pin state after the Stop condition has been sent to the device will not alter or interrupt the execution of the write cycle. The WP pin state must be valid with respect to the associated setup ($t_{SU.WP}$) and hold ($t_{HD.WP}$) timing as shown in Figure 5-5 below. The WP setup time is the amount of time that the WP state must be stable before the Stop condition is issued. The WP hold time is the amount of time after the Stop condition that the WP must remain stable (see Table 8-3, "AC Characteristics," on page 15 for timing specs for $t_{HD.WP}$ and $t_{SU.WP}$).

If an attempt is made to write to the device while the WP pin has been asserted (at V_{CC}), the device will acknowledge the device address, word address bytes, and data bytes, but no write cycle will occur when the Stop condition is issued, and the device will immediately be ready to accept a new Read or Write command.

Figure 5-5.   Write Protect Setup and Hold Timing
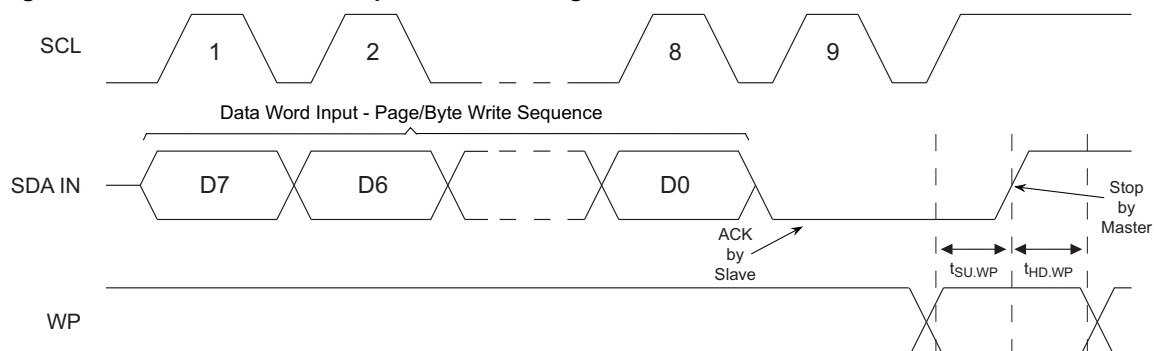
6. Read Operations

Read operations are initiated the same way as write operations with the exception that the read/write select bit in the device address word must be a Logic 1. There are three read operations: Current Address Read, Random Address Read, and Sequential Read.

6.1 Current Address Read

The internal data word address counter maintains the last address accessed during the last read or write operation, incremented by one. This address stays valid between operations as long as V_{CC} is maintained to the part. The address "roll over" during read is from the last byte of the last page to the first byte of the first page of the memory.

A Current Address Read sequence will output data according to the location of the internal data word address counter. This is initiated with a Start condition, followed by a valid device address byte with the R/$\overline{W}$ bit set to Logic 1. The device will acknowledge this sequence and the current address data word is serially clocked out on the SDA line. All types of Read operations will be terminated if the bus Master does not respond with an ACK (it NACKs) during the ninth clock cycle, which will force the device into standby mode. After the NACK response, the Master can send a Stop condition to complete the protocol, or it can send a Start condition to begin the next sequence.

While the two most significant bits of the data word address (A17 and A16) are embedded in the Device Address byte, they will not take precedence over the existing values of the A17 and A16 bits in the internal address counter during a Current Address Read and are therefore represented as don't care bits below in Figure 6-1.

Figure 6-1.   Current Address Read
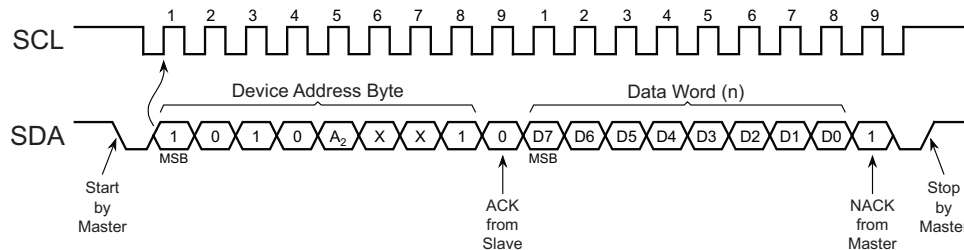
6.2 Random Read

A Random Read begins in the same way as a Byte Write operation to load in a new data word address. This is known as a "dummy write" operation. However, the Stop condition of the byte write must be omitted to prevent the part from entering an internal write cycle. Once the device address word and data word address are clocked in and acknowledged by the EEPROM, the bus Master must generate another Start condition.

The bus Master now initiates a Current Address Read by sending a Start condition, followed by a valid device address byte with the R/W bit set to Logic 1. While the two most significant bits of the data word address (A17 and A16) are embedded in the Device Address byte, they will not take precedence over the existing values of the A17 and A16 bits in the internal address counter set during the dummy write and are represented as don't care bits in Figure 6-2.

The EEPROM acknowledges the device address and serially clocks out the data word on the SDA line. The Random Read operation is terminated when the bus Master does not respond with an ACK (it NACKs) and generates a Stop condition in the next SCL clock cycle.

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Figure 6-2.   Random Read
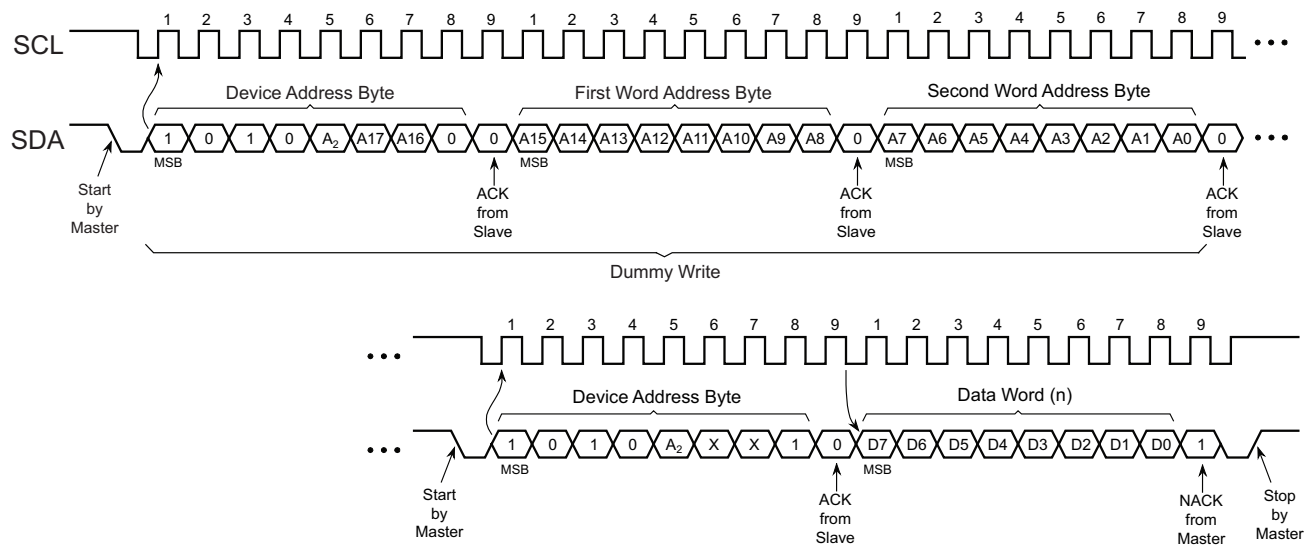
6.3   Sequential Read

Sequential Reads are initiated by either a Current Address Read or a Random Read that have been described previously. As such, the A17 and A16 bits sent in the Device Address byte are don't care values as they will not change the values in the address pointer. This is depicted in .

After the bus Master receives a data word, it responds with an acknowledge. As long as the EEPROM receives an acknowledge, it will continue to increment the data word address and serially clock out sequential data words. When the memory address maximum address is reached, the data word address will "roll over" and the sequential read will continue from the beginning of the memory array. The Sequential Read operation is terminated when the bus Master does not respond with an ACK (it NACKs) and generates a Stop condition in the next SCL clock cycle.

Figure 6-3.   Sequential Read
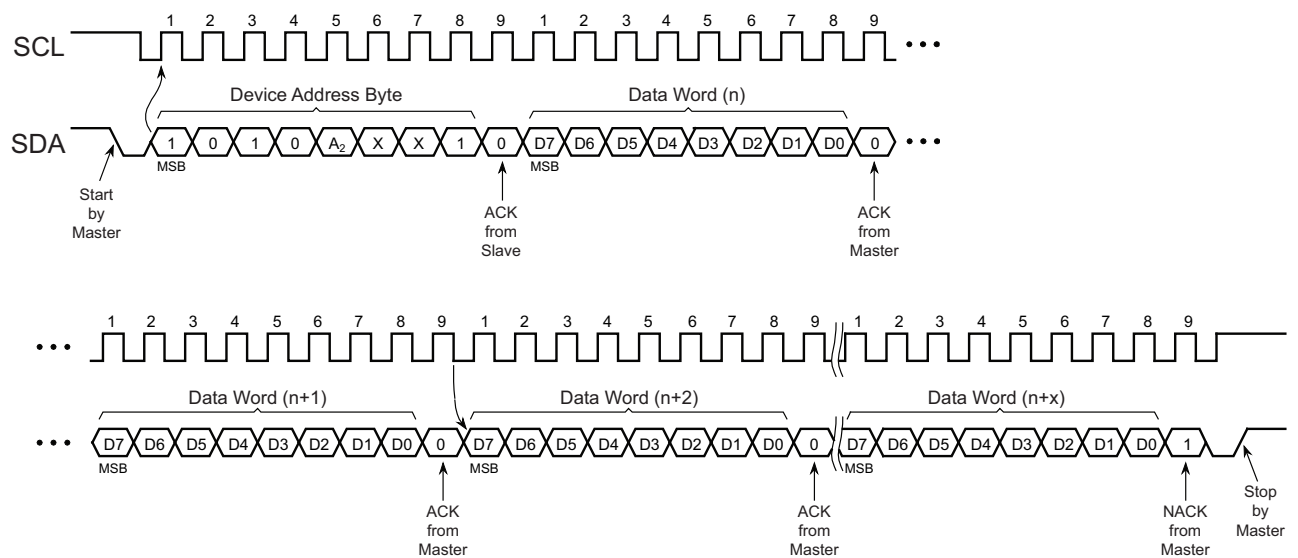
7.   Device Default Condition from Atmel

The AT24CM02 is delivered with the EEPROM array set to Logic 1, resulting in FFh data in all locations.

8. Electrical Specifications

8.1 Absolute Maximum Ratings

Temperature under Bias . . . . -55°C to +125°C

Storage Temperature . . . . -65°C to +150°C

Supply Voltage
with respect to ground . . . .-0.5V to +6.25V

Voltage on any pin
with respect to ground . . . .-1.0V to +7.0V

DC Output Current 5.0mA

Functional operation at the "Absolute Maximum Ratings" or any other conditions beyond those indicated in the operational range shown in Section 8.2 is not implied or guaranteed. Stresses beyond those listed under "Absolute Maximum Ratings" and/or exposure to the "Absolute Maximum Ratings" for extended periods may affect device reliability and cause permanent damage to the device.

Voltage extremes referenced in the "Absolute Maximum Ratings" are intended to accommodate short duration undershoot/overshoot pulses that the device may be subjected to during the course of normal operation and does not imply or guarantee functional device operation at these levels for any extended period of time.

8.2 DC and AC Operating Range

Table 8-1.   DC and AC Operating Range

		AT24CM02
Operating Temperature (Case)	Industrial Temperature Range	-40°C to +85°C
V_{CC} Power Supply	Low Voltage Grade	1.7V to 5.5V
	Standard Voltage Grade	2.5V to 5.5V

8.3 DC Characteristics

Table 8-2.   DC Characteristics

Parameter are applicable over operating range in Section 8.2, unless otherwise noted.

Symbol	Parameter	Test Condition		Min	Typical[1]	Max	Units
V_{CC1}	Supply Voltage			1.7		5.5	V
V_{CC2}				2.5		5.5	
I_{CC}	Supply Current, Read	V_{CC} = 1.8V[2]	Read at 400kHz		0.1	0.5	mA
		V_{CC} = 5.0V	Read at 1MHz		0.3	1.0	
I_{CC1}	Supply Current, Write	V_{CC} = 1.8V[2]	Averaged during t_{WR}		0.4	1.0	mA
		V_{CC} = 5.0V			1.7	3.0	
I_{SB}	Standby Current	V_{CC} = 1.8V[2]	V_{IN} = V_{CC} or V_{SS}		0.08	1.0	µA
		V_{CC} = 2.5V			0.08	2.0	
		V_{CC} = 5.5V			0.15	3.0	
I_{LI}	Input Leakage Current	V_{IN} = V_{CC} or V_{SS}			0.10	3.0	µA
I_{LO}	Output Leakage Current	V_{OUT} = V_{CC} or V_{SS}			0.05	3.0	
V_{IL}	Input Low Level[2]			–0.6		V_{CC} x 0.3	V
V_{IH}	Input High Level[2]			V_{CC} x 0.7		V_{CC} + 0.5	
V_{OL1}	Output Low Level	V_{CC} = 1.7V	I_{OL} = 0.15mA			0.2	V
V_{OL2}		V_{CC} = 3.0V	I_{OL} = 2.1mA			0.4	

Notes: 1.   Typical values characterized at T_A = +25°C unless otherwise noted.
2.   This parameter is characterized but is not 100% tested in production.

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8.4 AC Characteristics

Table 8-3. **AC Characteristics**

Parameters are applicable over operating range in Section 8.2 unless otherwise noted. Test conditions shown in Note 2.

Symbol	Parameter	Standard Mode V_{CC} = 1.7V to 5.5V		Fast Mode V_{CC} = 1.7V to 5.5V		Fast Mode Plus V_{CC} = 2.5V to 5.5V		Units
		Min	Max	Min	Max	Min	Max	
f_{SCL}	Clock Frequency, SCL		100		400		1000	kHz
t_{LOW}	Clock Pulse Width Low	4,700		1,300		500		ns
t_{HIGH}	Clock Pulse Width High	4,000		600		400		ns
t_I	Input Filter Spike Rejection (SCL, SDA)[1]		100		100		50	ns
t_{AA}	Clock Low to Data Out Valid		4,500		900		450	ns
t_{BUF}	Bus Free Time between Stop and Start[1]	4,700		1,300		500		ns
$t_{HD.STA}$	Start Hold Time	4,000		600		250		ns
$t_{SU.STA}$	Start Set-up Time	4,700		600		250		ns
$t_{HD.DAT}$	Data In Hold Time	0		0		0		ns
$t_{SU.DAT}$	Data In Set-up Time	200		100		100		ns
t_R	Inputs Rise Time[1]		1,000		300		100	ns
t_F	Inputs Fall Time[1]		300		300		100	ns
$t_{SU.STO}$	Stop Set-up Time	4,700		600		250		ns
$t_{SU.WP}$	Write Protect Setup Time	4,000		600		250		ns
$t_{HD.WP}$	Write Protect Hold Time	4,000		600		250		ns
t_{DH}	Data Out Hold Time	100		50		50		ns
t_{WR}	Write Cycle Time		10		10		10	ms

Notes: 1. These parameters are determined through product characterization and are not tested 100% in production.
2. AC measurement conditions:
- C_L : 100pF
- R_{PUP} (SDA bus line pull-up resistor to V_{CC}): 1.3 kΩ (1000kHz), 4kΩ (400kHz), 10kΩ (100kHz)
- Input pulse voltages: 0.3 V_{CC} to 0.7 V_{CC}
- Input rise and fall times: $\leq$ 50ns
- Input and output timing reference voltages: 0.5 x V_{CC}

Figure 8-1. **Bus Timing**
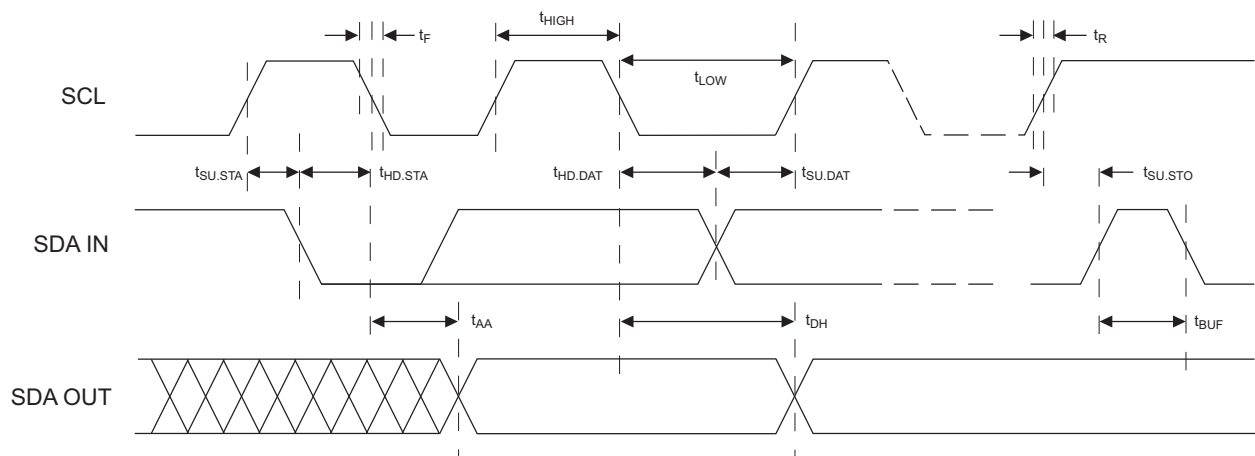
8.5 Power-Up Requirements and Reset Behavior

During a power-up sequence, the V_{CC} supplied to the AT24CM02 should monotonically rise from GND to the minimum V_{CC} level as specified in Section 8.2 on page 14, with a slew rate no faster than 0.1V/μs.

8.5.1 Device Reset

To prevent inadvertent write operations or any other spurious events from occurring during a power-up sequence, the AT24CM02 includes a power-on-reset (POR) circuit. Upon power-up, the device will not respond to any commands until the V_{CC} level crosses the internal voltage threshold (V_{POR}) that brings the device out of reset and into standby mode.

The system designer must ensure that no instruction is sent to the device until the V_{CC} supply has reached a stable value greater than the minimum V_{CC} level. Additionally, once the V_{CC} supply has surpassed the minimum V_{CC} level, the bus Master must wait at least t_{PUP} before sending the first command to the device. See Table 8-4 for the values associated with these power-up parameters.

Table 8-4.   Power-up Conditions[1]

Symbol	Parameter	Min	Max	Units
t_{PUP}	Time required after V_{CC} is stable before the device can accept commands	100	—	μs
V_{POR}	Power-On Reset Threshold Voltage	—	1.5	V
t_{POFF}	Minimum time at V_{CC} = 0V between power cycles	1	—	ms

Note: 1.   These parameters are characterized but they are not 100% tested in production.

If an event occurs in the system where the V_{CC} level supplied to the AT24CM02 drops below the maximum V_{POR} level specified, it is recommended that a full power cycle sequence be performed by first driving the V_{CC} pin to GND, waiting at least the minimum t_{POFF} time, and then performing a new power-up sequence in compliance with the requirements defined in this section.

8.6 Pin Capacitance

Table 8-5.   Pin Capacitance[1]

Applicable over recommended operating range from T_A = 25°C, f = 1.0MHz, V_{CC} = 5.5V

Symbol	Test Condition	Max	Units	Conditions
$C_{I/O}$	Input/Output Capacitance (SDA)	8	pF	$V_{I/O}$ = 0V
C_{IN}	Input Capacitance (A_2, SCL)	6	pF	V_{IN} = 0V

Note: 1.   This parameter is characterized and is not 100% tested.

8.7 EEPROM Cell Performance Characteristics

Table 8-6.   EEPROM Cell Performance Characteristics

Operation or Parameter	Test Condition	Min	Max	Units
Write Endurance[1]	T_A = 25°C, V_{CC}(min) < V_{CC} < V_{CC}(max) Byte[2] or Page Write Mode	1,000,000	—	Write Cycles
Data Retention[3]	T_A = 55°C, V_{CC}(min) < V_{CC} < V_{CC}(max)	100	—	Years

Notes: 1.   The Write endurance is determined through product characterization and the qualification process.
2.   Due to the memory array architecture, the Write Cycle Endurance is specified for writes in groups of 4 data bytes. The beginning of any 4-byte boundaries can be determined by multiplying any integer (N) by four (i.e. 4*N). The end address can be found by adding three to the beginning value (i.e. 4*N+3). See Section 5.3 "Internal Writing Methodology" on page 10 for more details on this implementation.
3.   The data retention capability is determined by qualification and checked on each device during production.

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9. Ordering Code Detail

A T 2 4 C M 0 2 - S S H M x x - T

Atmel Designator

Product Family
24C = Standard
    Serial EEPROM

Device Density
M = Megabit Family
02 = 2 Megabit

Shipping Carrier Option
T = Tape and reel
B = Bulk (tubes)

Product Variation
xx = Applies to select packages only.
     See ordering table for variation
     details.

Operating Voltage
M = 1.7V to 5.5V
D = 2.5V to 5.5V

**Package Device Grade or
Wafer/Die Thickness**
U = Green, SnAgCu WLCSP ball
     Industrial Temperature range
     (-40°C to +85°C)
H = Green, NiPdAu lead finish
     Industrial Temperature range
     (-40°C to +85°C)
11 = 11mil wafer thickness

Package Option
SS   = JEDEC SOIC
U1   = 8-ball, 4x4 Grid, Thin WLCSP
U2   = 8-ball, 4x4 Grid, Standard WLCSP
WWU= Wafer unsawn

10. Ordering Code Information

Atmel Ordering Code	Lead Finish	Package	Voltage	Delivery Information		Operation Range
				Form	**Quantity**	
AT24CM02-SSHM-T	NiPdAu Lead-free/Halogen-free	8S1	1.7V to 5.5V	Tape and Reel	4,000 per Reel	Industrial Temperature (-40°C to 85°C)
AT24CM02-SSHM-B				Bulk (Tubes)	100 per Tube	
AT24CM02-SSHD-T			2.5V to 5.5V	Tape and Reel	4,000 per Reel	
AT24CM02-SSHD-B				Bulk (Tubes)	100 per Tube	
AT24CM02-U1UM0B-T[1][2]	SnAgCu Ball Lead-free/Halogen-free	8U-11	1.7V to 5.5V	Tape and Reel	5,000 per Reel	
AT24CM02-U2UM-T[2]		8U-18				
AT24CM02-WWU11M[2]	N/A	Wafer Sale		Note 3		

Notes: 1. This device includes a backside coating to increase product robustness.

2. **CAUTION:** Exposure to ultraviolet (UV) light can degrade the data stored in EEPROM cells. Therefore, customers who use a WLCSP package or the product at a die level must ensure that exposure to ultraviolet light does *not* occur.

3. For wafer sales, please contact Atmel Sales

.

Package Type	
8S1	8-lead, 0.150" wide, Plastic Gull Wing Small Outline (JEDEC SOIC)
8U-11	8-ball, 4 x 4 Ball Grid Array, 0.5mm Pitch, Thin Wafer Level Chip Scale Package (WLCSP)
8U-18	8-ball, 4 x 4 Ball Grid Array, 0.5mm Pitch, Standard Thickness Wafer Level Chip Scale Package (WLCSP)

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11. Part Markings

AT24CM02: Package Marking Information

8-lead SOIC	8-ball WLCSP Thin and Standard Thickness Options
ATMLHYWW ## % @ AAAAAAAA	ATMLUYWW ## % @ AAAAAA
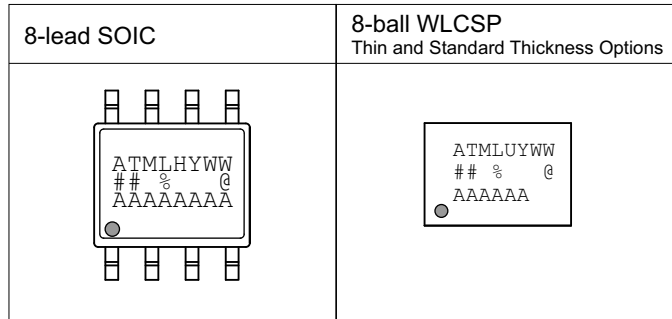
Note 1: ⬤ designates pin 1
Note 2: Package drawings are not to scale

Catalog Number Truncation			
AT24CM02	Truncation Code ##: 2H		

Date Codes		Voltages	
Y = Year	WW = Work Week of Assembly	% = Minimum Voltage	
5: 2015　　9: 2019 6: 2016　　0: 2020 7: 2017　　1: 2021 8: 2018　　2: 2022	02: Week 2 04: Week 4 ... 52: Week 52	M:　1.7V min D:　2.5V min	

Country of Assembly	Lot Number	Grade/Lead Finish Material
@ = Country of Assembly	AAA...A = Atmel Wafer Lot Number	H:　Industrial/NiPdAu U:　Industrial/SnAgCu
		Atmel Truncation
		ATML:　Atmel

4/7/2016

Atmel Package Mark Contact: DL-CSO-Assy_eng@atmel.com	TITLE 24CM02SM, AT24CM02 Package Marking Information	DRAWING NO. 24CM02SM	REV. F

12. Packaging Information

12.1 8S1 — 8-lead JEDEC SOIC

TOP VIEW

END VIEW

SIDE VIEW

Notes: This drawing is for general information only.
Refer to JEDEC Drawing MS-012, Variation AA
for proper dimensions, tolerances, datums, etc.

COMMON DIMENSIONS
(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
A	–	–	1.75	
A1	0.10	–	0.25	
b	0.31	–	0.51	
C	0.17	–	0.25	
D		4.90 BSC		
E		6.00 BSC		
E1		3.90 BSC		
e		1.27 BSC		
L	0.40	–	1.27	
Ø	0°	–	8°	

3/6/2015

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Package Drawing Contact:
packagedrawings@atmel.com

TITLE	GPC	DRAWING NO.	REV.
8S1, 8-lead (0.150" Wide Body), Plastic Gull Wing Small Outline (JEDEC SOIC)	SWB	8S1	H

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12.2   8U-11 — 8-ball WLCSP

TOP VIEW

⌓ 0.015 (4X)

A1 CORNER

1 2   3 4   A

A
B
C
D

E

D   B

SIDE VIEW

A   A2

SEATING PLANE

C

A1

⌓ 0.20 C

PIN ASSIGNMENT MATRIX

	1	2	3	4
A	n/a	V_{CC}	NC	n/a
B	n/a	WP	n/a	NC
C	SCL	n/a	n/a	A_2
D	n/a	SDA	GND	n/a

NC = Not Connected

BOTTOM SIDE

4 3   2 1   A1 CORNER

A
B

+

e1

C
D

e

d1
d2

⊕	∅ 0.015 Ⓜ C
	∅ 0.05 Ⓜ C A B

COMMON DIMENSIONS
(Unit of Measure = mm)

SYMBOL	MIN	TYP	MAX	NOTE
A	0.313	0.334	0.355	
A1	—	0.094	—	
A2	—	0.240	—	3
D	Contact Atmel for details			
d1	1.00 BSC			
d2	1.40 BSC			
E	Contact Atmel for details			
e	0.50 BSC			
e1	2.10 BSC			
b	0.170	0.185	0.200	

Note: 1. Dimensions are NOT to scale.
2. Solder ball composition is 95.5Sn-4.0Ag-0.5Cu.
3. Product offered with Back Side Coating.

8/7/15

Atmel Package Drawing Contact: packagedrawings@atmel.com	TITLE 8U-11, 8-ball 4x4 Array, Custom Pitch Wafer Level Chip Scale Package (WLCSP) with BSC	GPC GEN	DRAWING NO. 8U-11	REV. E

12.3 8U-18 — 8-ball WLCSP

TOP VIEW

BOTTOM SIDE

0.015 (4X)
A

A1 CORNER
1 2   3 4

A
B

E

C
D

D

4 3   2 1   A1 CORNER

A
B

+

C
D

e1

e

⌀b

d1
d2

⌀0.015 Ⓜ C
⌀0.05 Ⓜ C A B

SIDE VIEW
A2

SEATING PLANE
A
-C-

A1

0.20 C

PIN ASSIGNMENT MATRIX

	1	2	3	4
A	n/a	V_{cc}	NC	n/a
B	n/a	WP	n/a	NC
C	SCL	n/a	n/a	A_2
D	n/a	SDA	GND	n/a

NC = Not Connected

COMMON DIMENSIONS
(Unit of Measure = mm)

SYMBOL	MIN	TYP	MAX	NOTE
A	0.456	0.495	0.534	
A1	—	0.190	—	
A2	—	0.305	—	
D	Contact Atmel for details.			
d1	1.00 BSC			
d2	1.40 BSC			
E	Contact Atmel for details.			
e	0.50 BSC			
e1	2.10 BSC			
b	—	0.270	—	

Note: 1. Dimensions are NOT to scale.
2. Solder ball composition is 95.5Sn-4.0Ag-0.5Cu.

4/5/16

Atmel Package Drawing Contact: packagedrawings@atmel.com	TITLE 8U-18, 8-ball 4x4 Array, Custom Pitch Wafer Level Chip Scale Package (WLCSP)	GPC GQA	DRAWING NO. 8U-18	REV. 01

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13. Revision History

Doc. Rev.	Date	Comments
8828E	01/2017	Updated Power On Requirements and Reset Behavior section
8828D	05/2016	Added the 8U-18 standard thickness WLCSP package option. Updated the "Clock and Data Transition Requirements" section and the "DC Characteristics" table.
8828C	11/2015	Corrected 8-ball WLCSP pinout.
8828B	08/2015	Updated the 8U-11 package drawing, data retention discrepancy, and 8-ball pinout.
8828A	05/2015	Initial document release.